

OptiMOS[™]3 Power-Transistor

Features

- Fast switching MOSFET for SMPS
- Optimized technology for DC/DC converters
- Qualified according to JEDEC¹⁾ for target applications
- N-channel, logic level
- Excellent gate charge x R_{DS(on)} product (FOM)
- Very low on-resistance R_{DS(on)}
- 100% Avalanche tested
- Pb-free plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

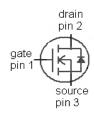
Product Summary

V _{DS}	40	V
R _{DS(on),max}	3.9	mΩ
I _D	80	Α





Туре	IPB039N04L G	IPP039N04L G
	1 3 (tab)	123
Package	PG-TO263-3	PG-TO220-3
Marking	039N04L	039N04L



Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	V _{GS} =10 V, T _C =25 °C	80	А
		V _{GS} =10 V, T _C =100 °C	80	
		V _{GS} =4.5 V, T _C =25 °C	80	
		V _{GS} =4.5 V, T _C =100 °C	73	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	400	
Avalanche current, single pulse ³⁾	IAS	T _C =25 °C	80	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =80 A, $R_{\rm GS}$ =25 Ω	60	mJ
Gate source voltage	V_{GS}		±20	V

¹⁾ J-STD20 and JESD22



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P_{tot}	T _C =25 °C	94	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R_{thJC}		1	1	1.6	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	1	1	62	
		6 cm² cooling area ⁴⁾	1	1	40	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ =45 $\mu {\rm A}$	1.2	1	2	
Zero gate voltage drain current	I _{DSS}	V _{DS} =40 V, V _{GS} =0 V, T _j =25 °C	1	0.1	1	μΑ
		V _{DS} =40 V, V _{GS} =0 V, T _j =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	10	100	nA
Drain-source on-state resistance ⁵⁾	R _{DS(on)}	V _{GS} =4.5 V, I _D =80 A	-	4.2	5.2	mΩ
		V _{GS} =10 V, I _D =80 A	-	3.1	3.9	
Gate resistance	R _G		-	1.6	-	Ω
Transconductance	g fs	V _{DS} >2 I _D R _{DS(on)max} , I _D =80 A	75	151	-	s

²⁾ See figure 3 for more detailed information

³⁾ See figure 13 for more detailed information

 $^{^{4)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

⁵⁾ Measured from drain tab to source pin



Parameter	Symbol	Conditions		Values		Uni
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C _{iss}		-	4600	6100	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	820	1100	
Reverse transfer capacitance	C _{rss}		-	39	-	
Turn-on delay time	$t_{d(on)}$		-	10	-	ns
Rise time	tr	V _{DD} =20 V, V _{GS} =10 V,	-	5.4	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_{\rm D}$ =30 A, $R_{\rm G}$ =1.6 Ω	-	38	-	
Fall time	t_{f}		-	6.0	-	
Gate Charge Characteristics ⁶⁾	•					
Gate to source charge	Q _{gs}		1	14	-	nC
Gate charge at threshold	Q _{g(th)}		-	7.4	-	
Gate to drain charge	Q _{gd}	V _{DD} =20 V, I _D =30 A,	-	6.1	-	
Switching charge	Q _{sw}	V _{GS} =0 to 10 V	-	13	-	
Gate charge total	Qg		-	59	78	
Gate plateau voltage	$V_{ m plateau}$		-	3.0	-	٧
Gate charge total	Qg	V _{DD} =20 V, I _D =30 A, V _{GS} =0 to 4.5 V	-	28	38	nC
Gate charge total, sync. FET	Q _{g(sync)}	V _{DS} =0.1 V, V _{GS} =0 to 10 V	-	55	-	
Output charge	Q _{oss}	V _{DD} =20 V, V _{GS} =0 V	-	42	-	
Reverse Diode				•		
Diode continuous forward current	Is	T -25 °C	-	-	78	Α
Diode pulse current	I _{S,pulse}	- T _C =25 °C	-	-	400	
Diode forward voltage	V_{SD}	V _{GS} =0 V, I _F =80 A, T _j =25 °C	-	0.92	1.2	V
Reverse recovery charge	Q _{rr}	V_{R} =20 V, I_{F} = I_{S} , di_{F} / dt =400 A/ μ s	-	50	-	nC

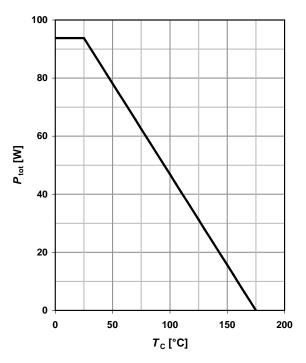
⁶⁾ See figure 16 for gate charge parameter definition





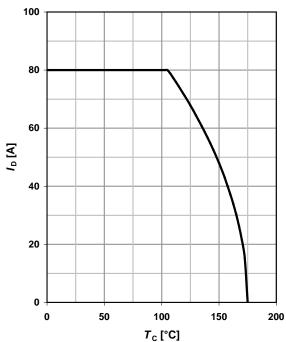
1 Power dissipation

P_{tot} =f(T_{C})



2 Drain current

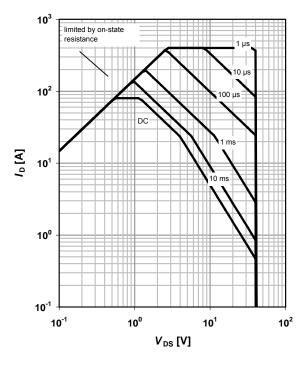
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

$$I_{\rm D}$$
=f($V_{\rm DS}$); $T_{\rm C}$ =25 °C; D =0

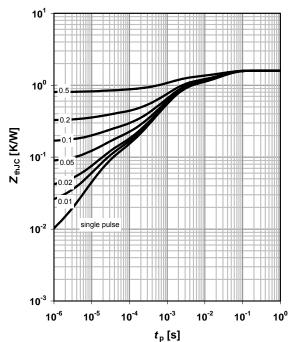
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{\rm thJC}$$
=f($t_{\rm p}$)

parameter: $D = t_p/T$

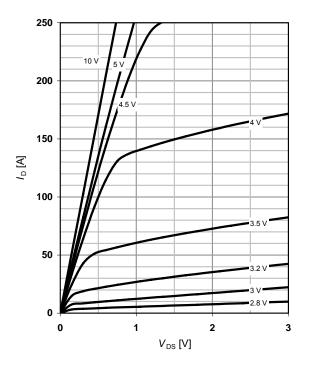




5 Typ. output characteristics

 I_D =f(V_{DS}); T_j =25 °C

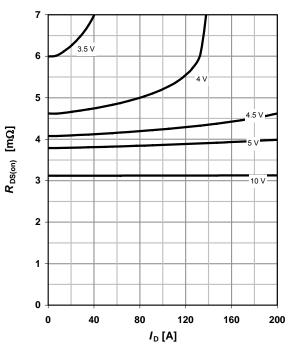
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

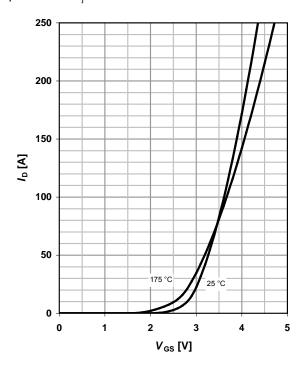
parameter: V_{GS}



7 Typ. transfer characteristics

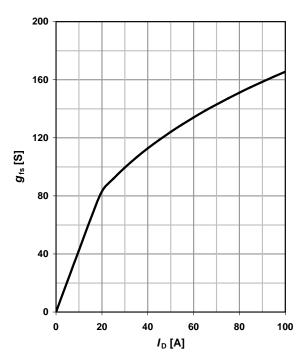
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

parameter: $T_{\rm j}$



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C



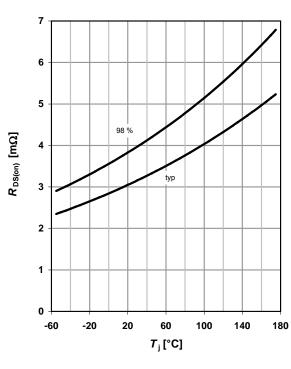


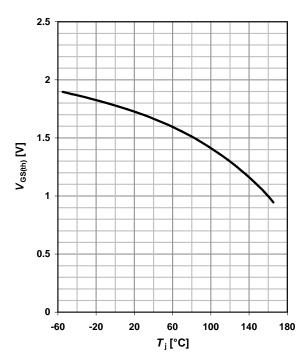
9 Drain-source on-state resistance

$$R_{DS(on)}$$
=f(T_j); I_D =80 A; V_{GS} =10 V

10 Typ. gate threshold voltage

$$V_{\mathrm{GS(th)}} = f(T_{\mathrm{j}}); \ V_{\mathrm{GS}} = V_{\mathrm{DS}}; \ I_{\mathrm{D}} = 250 \ \mu\mathrm{A}$$





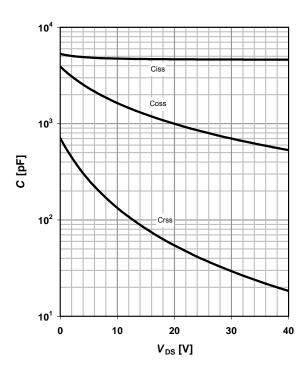
11 Typ. capacitances

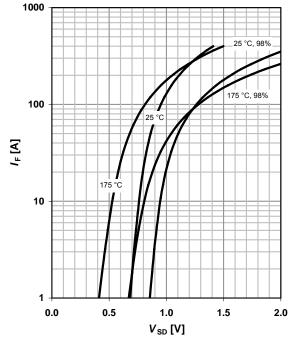
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$

12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter: $T_{\rm j}$







13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

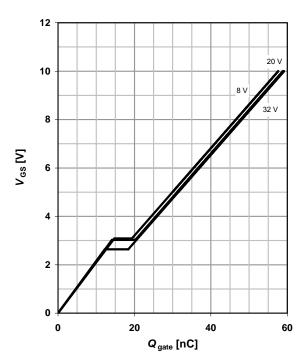
parameter: $T_{j(start)}$

100 25 °C 25 °C 100 °C 25 °C 100 °C 150 °C 1

14 Typ. gate charge

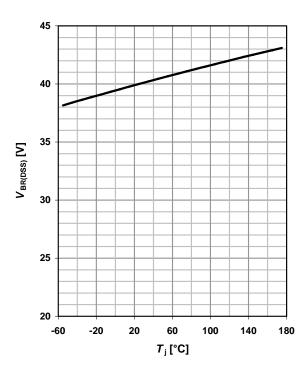
 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =30 A pulsed

parameter: $V_{\rm DD}$

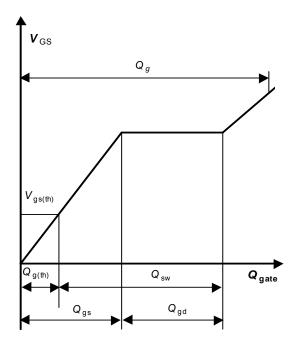


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_i); I_D =1 mA



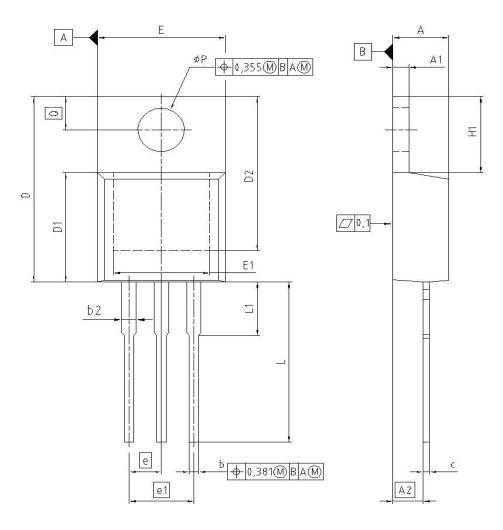
16 Gate charge waveforms





Package Outline

PG-TO220-3-1



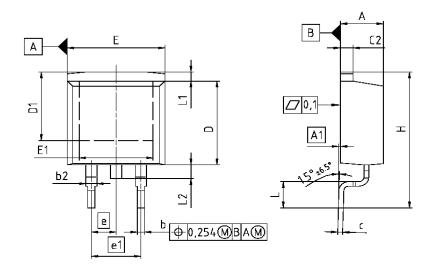
BUR	DIM MILLIMETERS		MILLIMETERS	INCH	HES .
DIN	MIN	MAX	MIN	MAX	
Α	4.300	4.572	0.169	0.180	
A1	1.170	1.400	0.046	0.055	
A2	2.215	2.718	0.087	0.107	
b	0.650	0.864	0.026	0.034	
b2	0.635	1.778	0.025	0.070	
C	0.330	0.600	0.013	0.024	
D	14.808	15.950	0.583	0.628	
D1	8.509	9.450	0.335	0.372	
D2	12.850	13.100	0.506	0.516	
E	9.700	10.363	0.382	0.408	
E1	6.500	8.600	0.256	0.339	
е	2.5	540	0.1	00	
e1	5.0	080	0.2	100	
N		3	;	3	
H1	5.900	6.900	0.232	0.272	
L	13.000	14.000	0.512	0.551	
L1		4.800		0.189	
ρP	3.700	3.886	0.146	0.153	
Q	2.600	3.000	0.102	0.118	

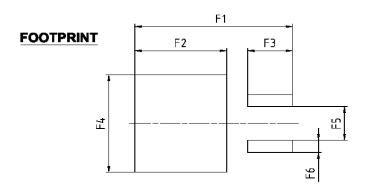
REFERE	NCE
JEDEC T	O220
SCALE	2.5
0 2.5 	
EUROPEAN PI	ROJECTION
-	—
1 SSUE D 01-06-2	
FILI	
TO22	0 1



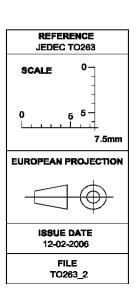
Package Outline

PG-TO263-3





ым	MILLIM	IETERS	INC	HES
Dillin	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	0.000	0.254	0.000	0.010
b	0.650	0.850	0.026	0.033
b2	0.950	1.321	0.037	0.052
С	0.330	0.650	0.013	0.026
c2	0.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	7.100	-	0.280	-
E	9.800	10.312	0.386	0.406
E1	6.500		0.256	
	2.540		0.1	100
e1	5.080		0.200	
N	2			2
н	14.605	15.875	0.575	0.625
L	2.200	3.000	0.087	0.118
L1	-	1.600	-	0.063
L2	1.000	1.778	0.039	0.070
F1	16.050	16.250	0.632	0.640
F2	9.300	9.500	0.366	0.374
F3	4.500	4.700	0.177	0.185
F4	10.700	10.900	0.421	0.429
F5	3.630	3.830	0.143	0.151
F6	1.100	1.300	0.043	0.051





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